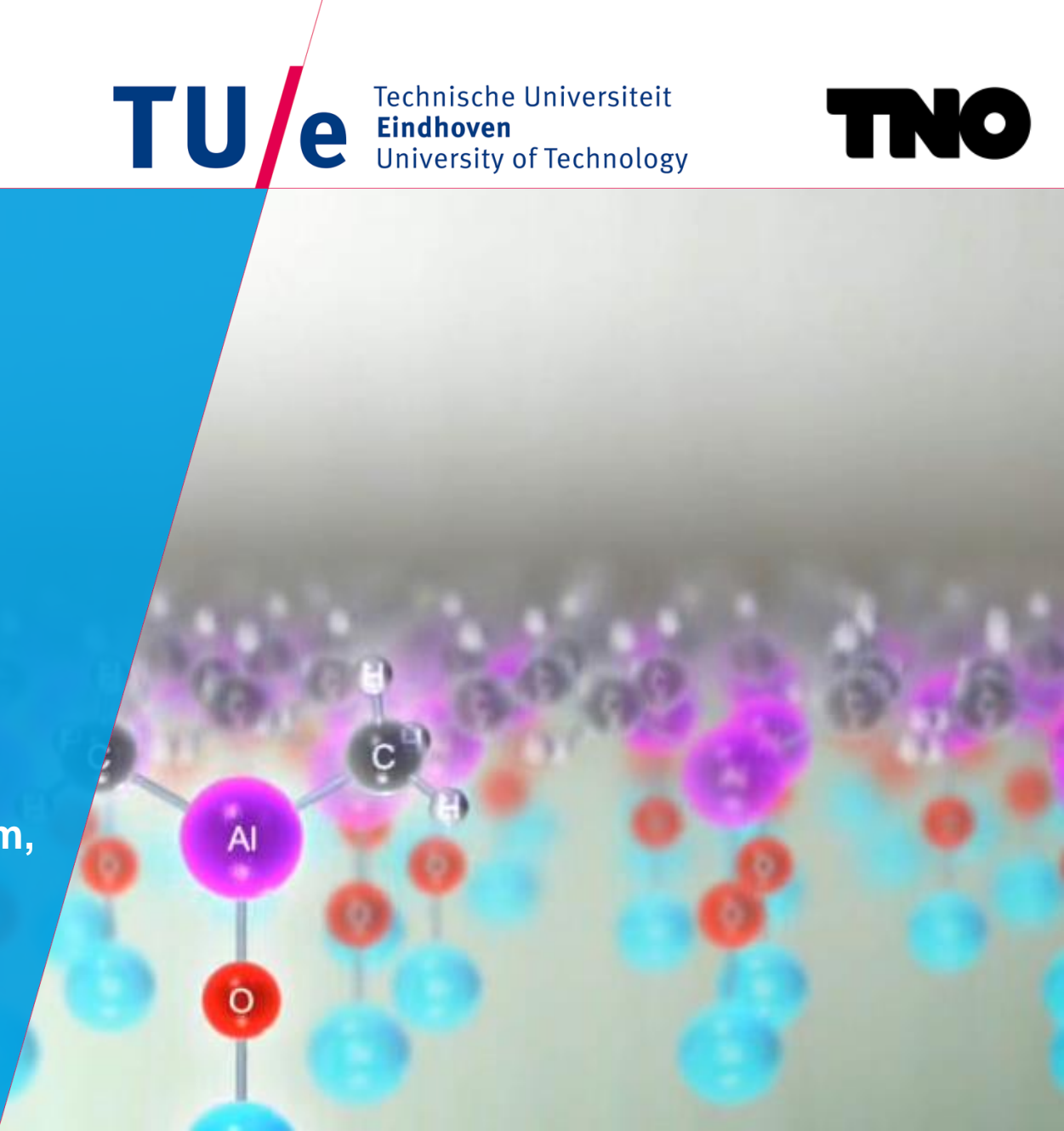


Area-selective ALD of SiO_2 using acetylacetone as inhibitor in a three-step cycle

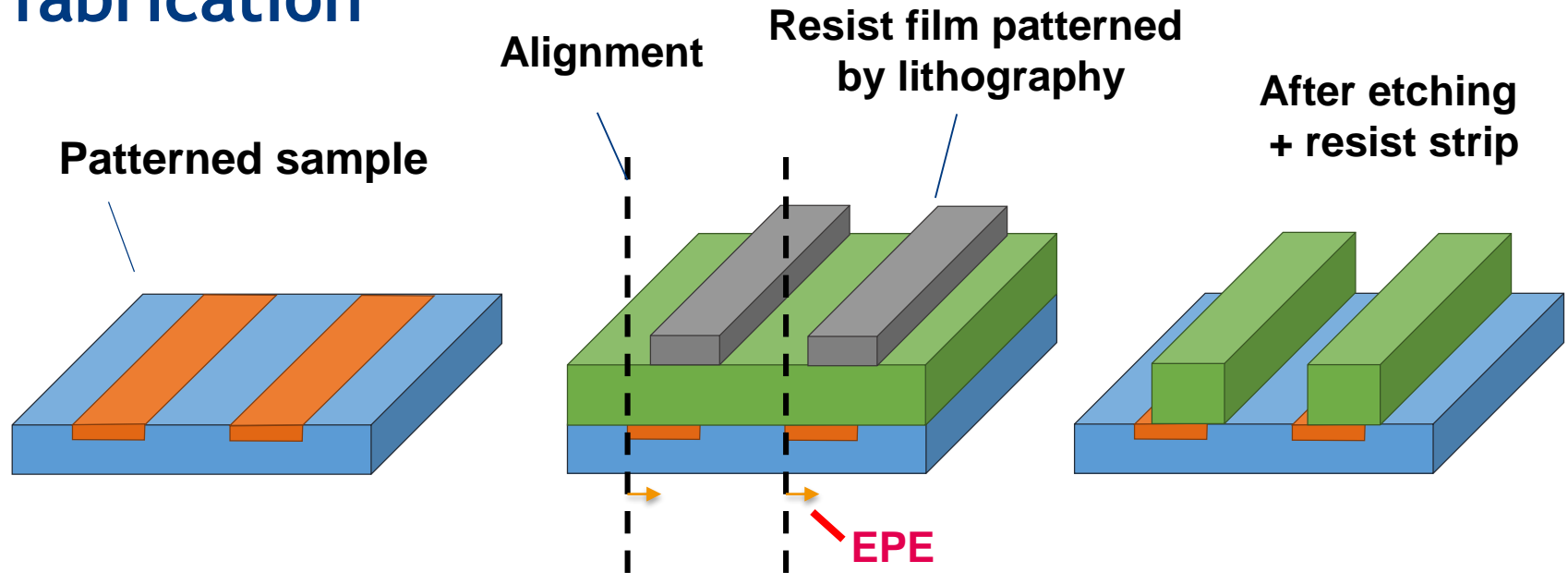
A. Mameli, M. Merkx,
B. Karasulu, F. Roozeboom,
W. M. M. Kessels, A. J. M.
Mackus

a.mameli@tue.nl

a.j.m.mackus@tue.nl



Area-selective deposition for self-aligned fabrication



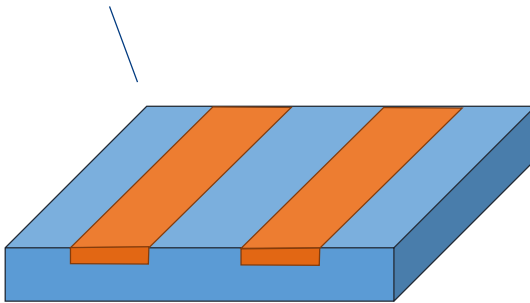
Device fabrication requires to deposit a certain material (green block) only on a certain surface (orange) while keeping clean the other surfaces

Standard approach: multi-step litho-etch litho-etch (LELE)

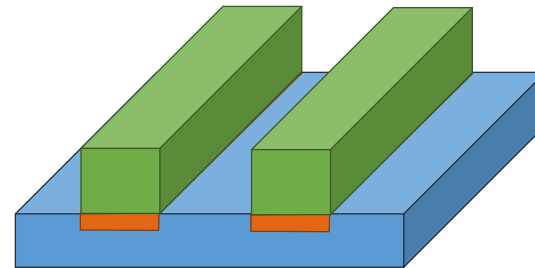
Challenge: the underlayer CD keep shrinking, leading to edge placement error (EPE)

Area-selective deposition for self-aligned fabrication

Patterned sample



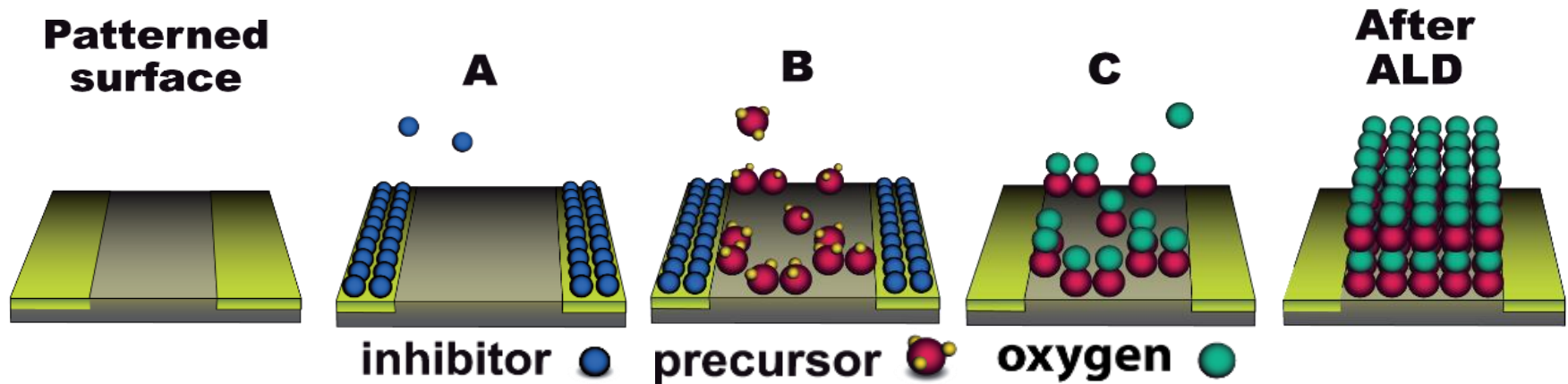
After area-selective deposition



Solution: Area-selective deposition (bottom-up approach)

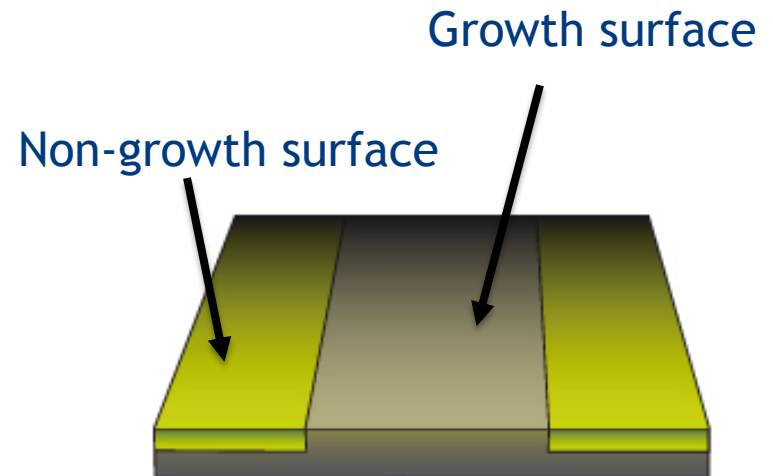
The green blocks are selectively deposited on the orange patterns ensuring perfect feature alignment

Approach: area selective ALD using molecular inhibitors in ABC processes

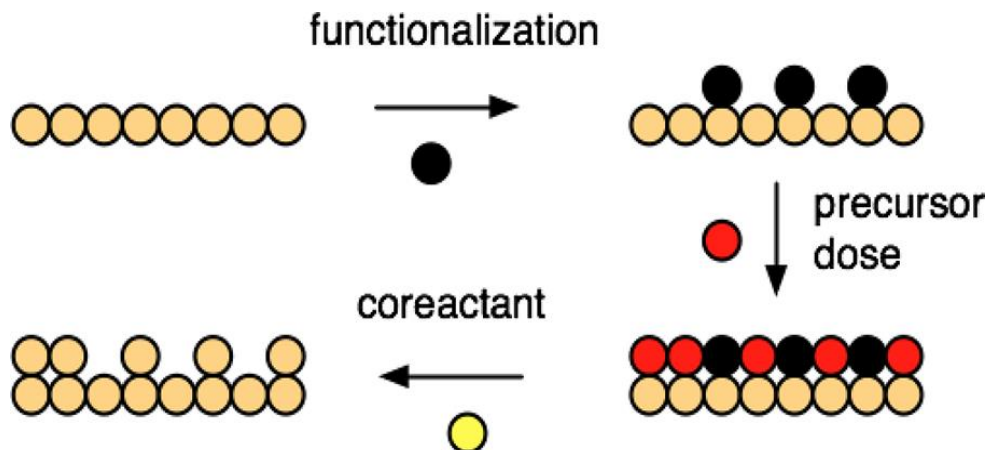


The inhibitor molecule:

- adsorbs on the non-growth surface
- blocks the adsorption of the precursor in the subsequent ALD cycle
- does not adsorb on the growth surface and the material to be deposited



ABC ALD processes with inhibitor molecules



Mechanism:

Reduction of available adsorption sites for the subsequent precursor (B) dose

Use of ABC ALD processes with A = inhibitor molecule has been shown to improve the doping efficiency

Table 2. Influence of Inhibitor on the Normalized Growth Per Cycle (GPC) Values for Selected Surface-Functionalized ALD Chemistries

#	precursor	inhibitor	norm. GPC
10	TMA	CH ₃ COOH	0.28
11	TMA	CH ₃ CN	1
12	TMA	MeOH	0.40
19	DEZ	MeOH	0.33
21	DEZ	iPrOH	0.59
22	TTIP	MeOH	0.22
23	TTIP	iPrOH	0.26
24	TiCl ₄	MeOH	0.26
25	TiCl ₄	iPrOH	0.67

Outline

Novel approach for achieving area-selective ALD using a three step (ABC) process

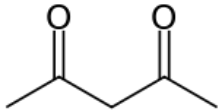
Proof of concept: area-selective ALD of SiO_2

How and why it works

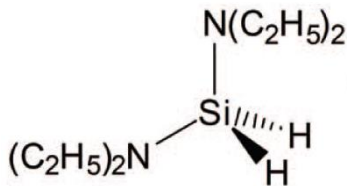
Process testing on patterned samples

Conclusions and opportunities of this approach

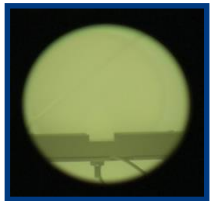
Selective growth of SiO₂



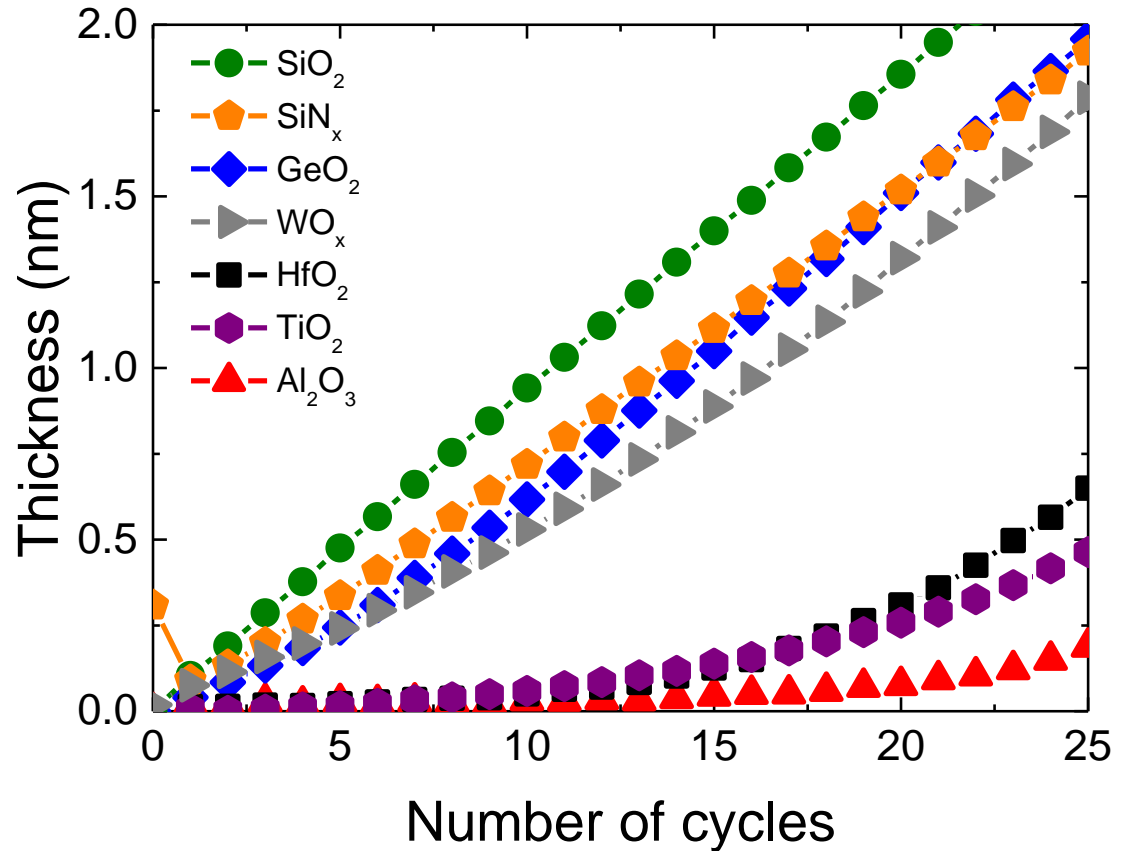
A =
Acetylacetone
(Hacac)



B =
BDEAS



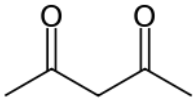
C =
O₂ plasma



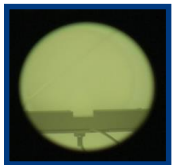
Fast nucleation on SiO₂ and Ge

Delay of 10 cycles on HfO₂ and 15 cycles on Al₂O₃

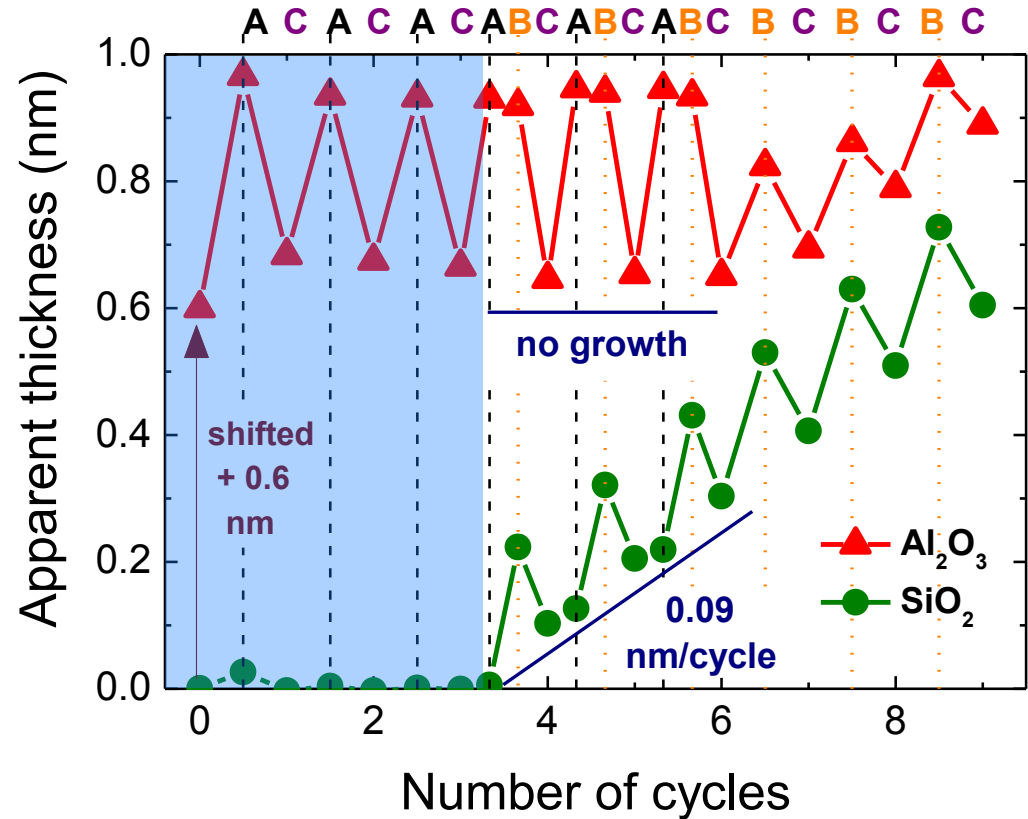
Sub-cycle ellipsometry data: case of Al_2O_3 and SiO_2



A = Hacac



C = O_2 plasma



AC cycles:

Selective adsorption of Hacac on Al_2O_3 and removal by O_2 plasma

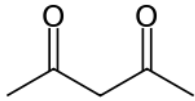
ABC cycles:

Adsorbed Hacac on Al_2O_3 blocks adsorption of BDEAS

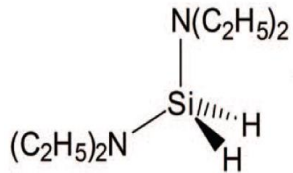
BC cycles:

Growth rate equal to ABC cycles on SiO_2

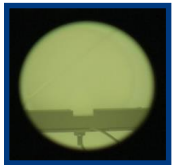
Sub-cycle ellipsometry data: case of Al_2O_3 and SiO_2



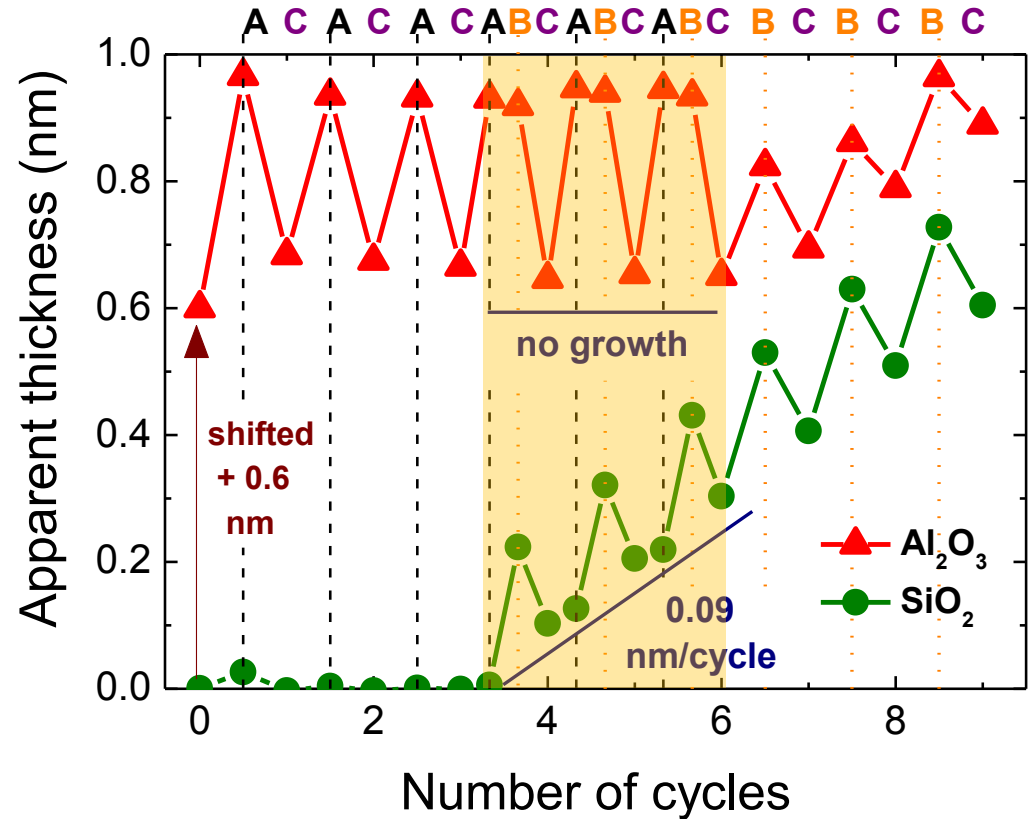
A = Hacac



B = BDEAS



C = O_2 plasma



AC cycles:

Selective adsorption of Hacac on Al_2O_3 and removal by O_2 plasma

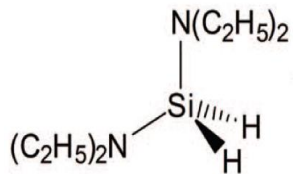
ABC cycles:

Adsorbed Hacac on Al_2O_3 blocks adsorption of BDEAS

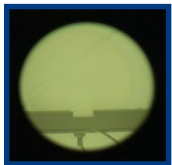
BC cycles:

Growth rate equal to ABC cycles on SiO_2

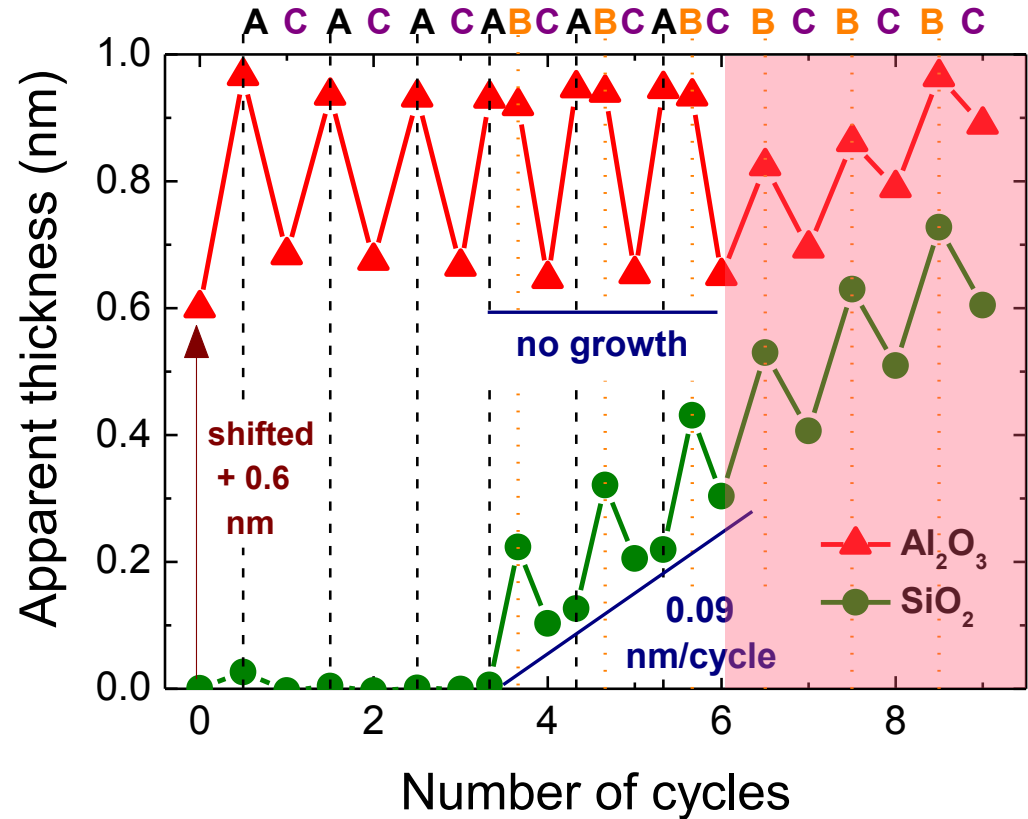
Sub-cycle ellipsometry data: case of Al_2O_3 and SiO_2



B = BDEAS



C = O_2 plasma



AC cycles:

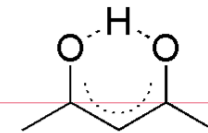
Selective adsorption of Hacac on Al_2O_3 and removal by O_2 plasma

ABC cycles:

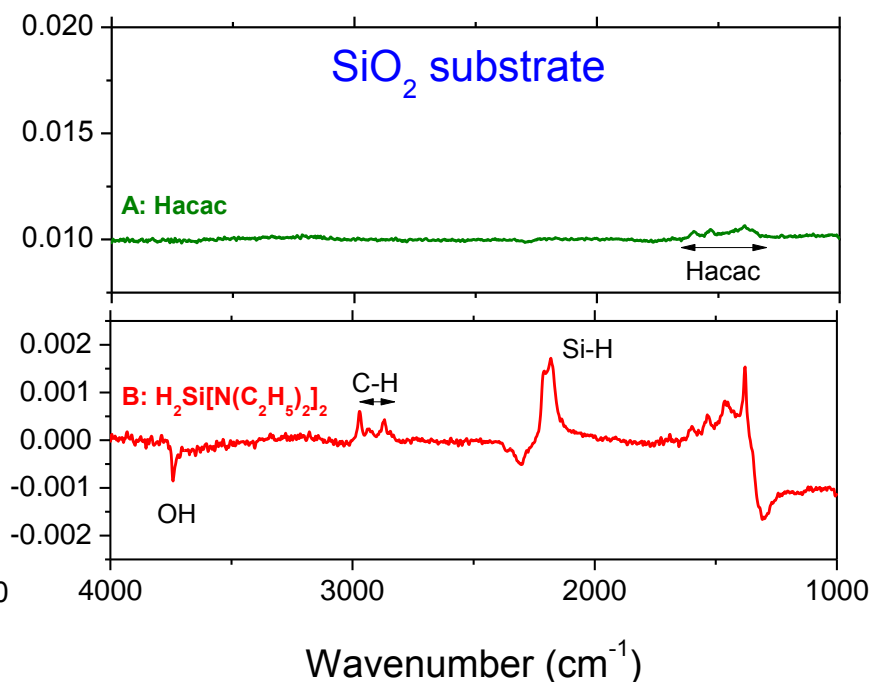
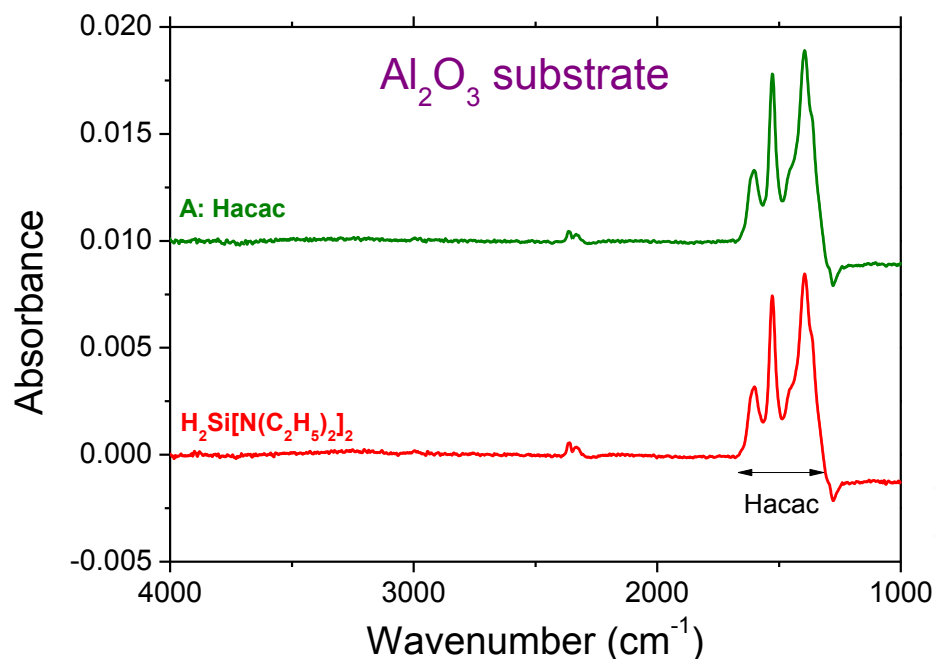
Adsorbed Hacac on Al_2O_3 blocks adsorption of BDEAS

BC cycles:

Growth rate equal to ABC cycles on SiO_2



In-situ Fourier transformed Infrared Spectroscopy

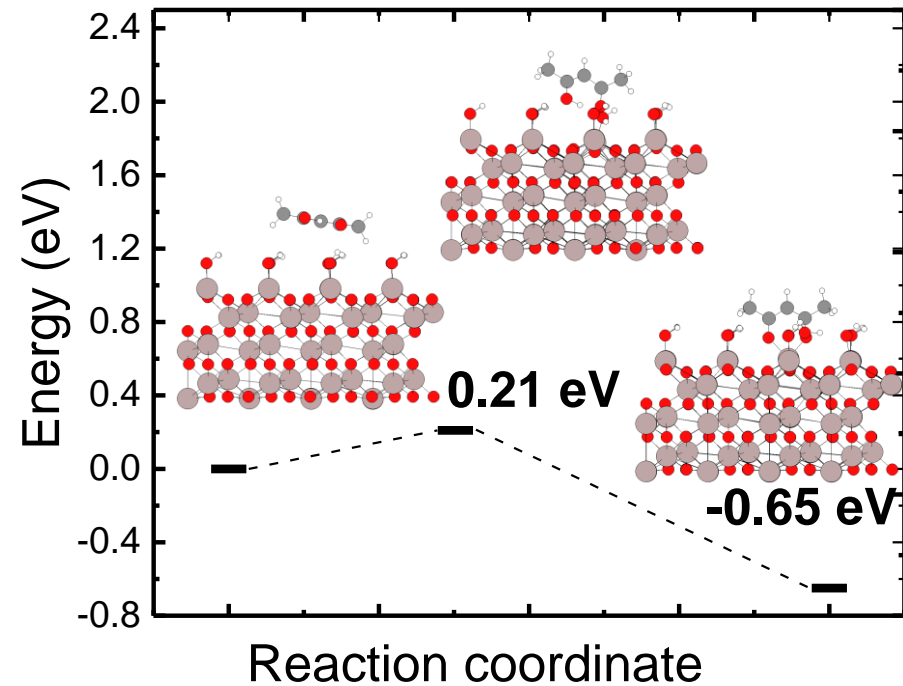


Hacac adsorbs on Al_2O_3
No detectable adsorption of BDEAS
on Al_2O_3 grafted with Hacac

Almost no adsorption of Hacac on SiO_2
adsorption of BDEAS on SiO_2 after
Hacac dose still possible

Density functional theory calculations

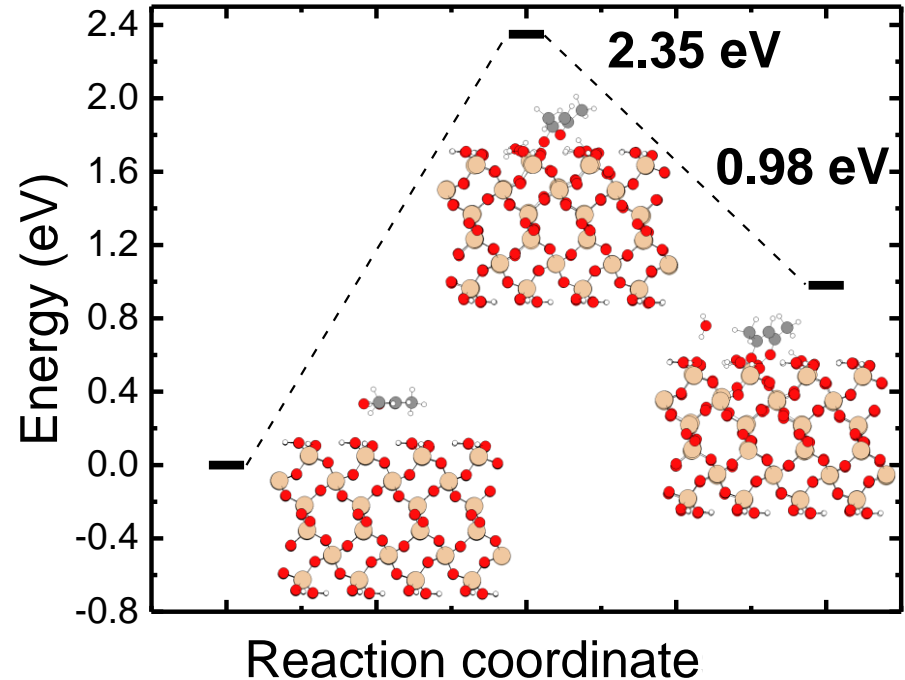
Hacac adorption on Al_2O_3



Low kinetic barrier

Thermodynamically favourable

Hacac adorption on SiO_2



High kinetic barrier

→ Kinetically hindered

Thermodynamically unfavourable

Outline

Novel approach for achieving area-selective ALD using a three step (ABC) process

Proof of concept: area-selective ALD of SiO_2

How and why it works

Process testing on patterned samples

Conclusions and opportunities of this approach

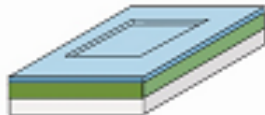
TOF-SIMS on $\text{Al}_2\text{O}_3/\text{GeO}_2$ patterned

Lift-off

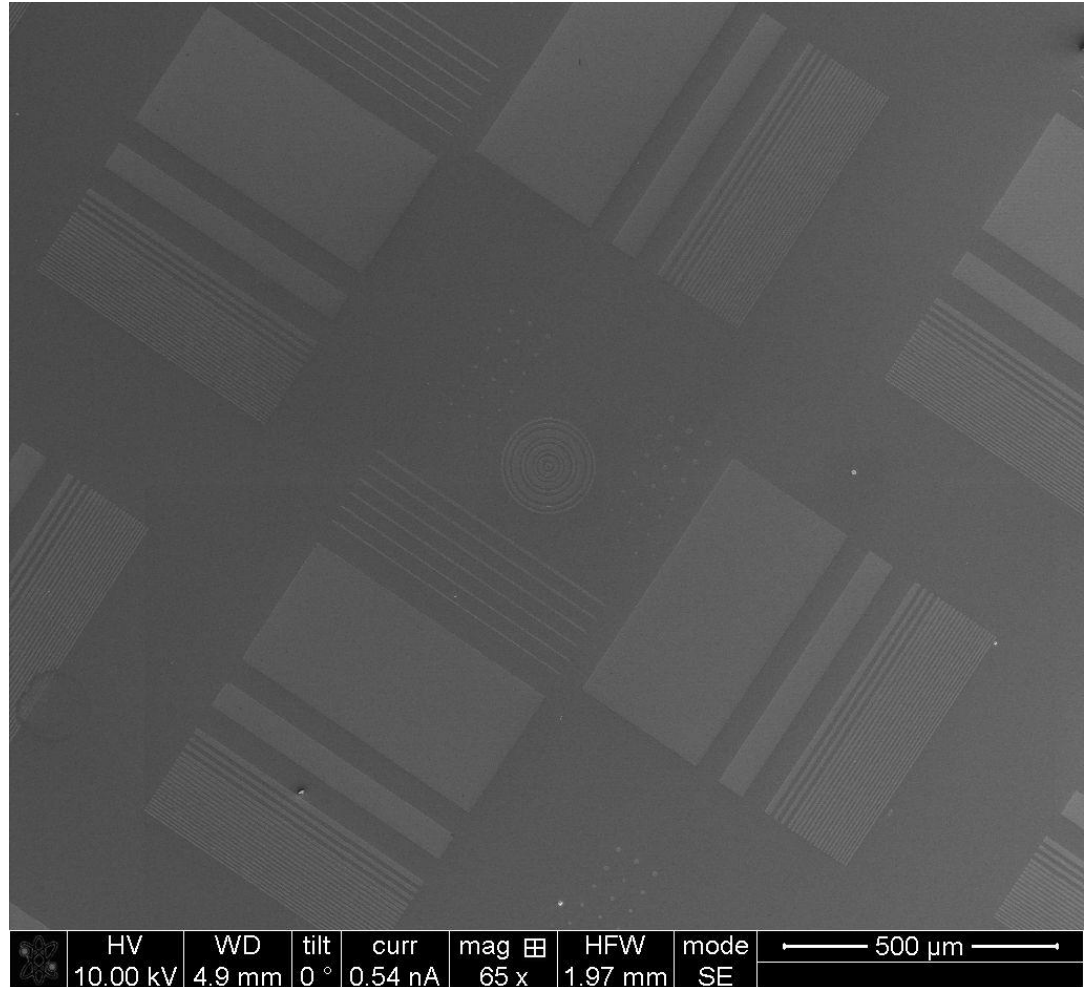
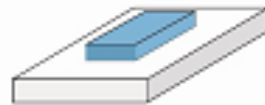
1. Resist patterning



2. ALD



3. Lift-off

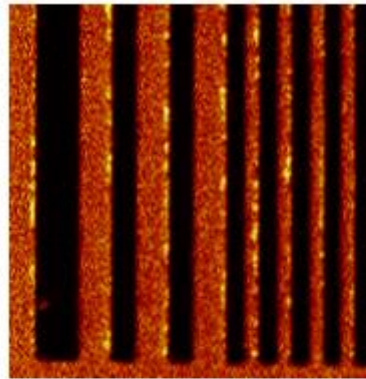


TOF-SIMS on $\text{Al}_2\text{O}_3/\text{GeO}_2$ patterned

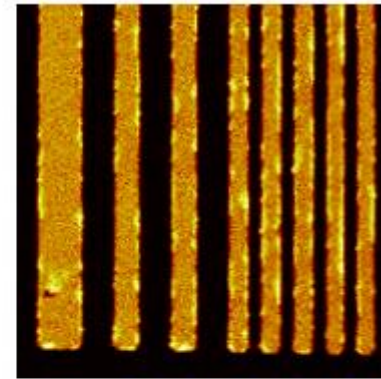
Using 12 cycles (ABC) AS-
ALD SiO_2 ~1 nm thick

Complementarity of Al^+
and Si^+ signals implies
that SiO_2 was deposited
on GeO_2 while almost
no deposition
occurred on Al_2O_3

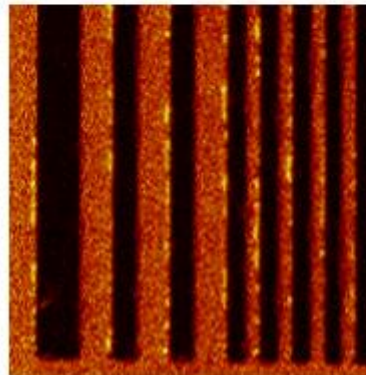
(a) Ge^+



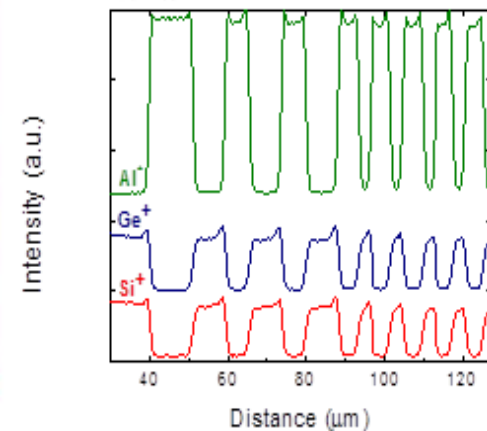
(b) Al^+



(c) Si^+



(d)



Conclusions

Novel ABC AS-ALD for SiO_2 exploiting selective adsorption of inhibitor molecules

A unique feature of this new approach is that it distinguishes between different oxide surfaces (e.g. $\text{GeO}_2/\text{SiO}_2$ versus $\text{Al}_2\text{O}_3/\text{HfO}_2/\text{TiO}_2$)

Moreover, in contrast to most other AS-ALD approaches, it is compatible with plasma-assisted or ozone-based ALD

Can open up new application opportunities for AS-ALD

It is expected that the approach can be extended to other materials, and potentially allows for tuning the selectivity by selecting opportune inhibitor molecules

Thank you for your kind attention

